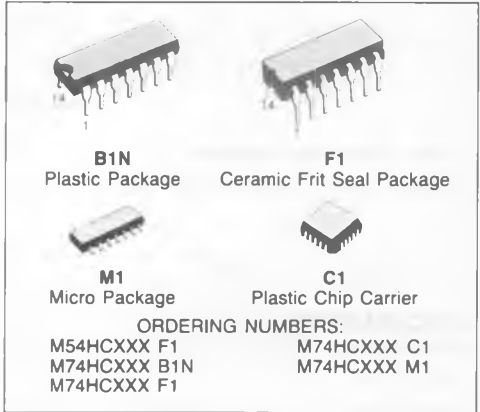


## QUAD BUS TRANSCEIVER (3-STATE)

PRELIMINARY DATA

- **HIGH SPEED**  
 $t_{PD} = 10 \text{ ns (TYP.) at } V_{CC} = 5 \text{ V}$
- **LOW POWER DISSIPATION**  
 $I_{CC} = 4 \mu\text{A (MAX.) at } T_A = 25^\circ\text{C}$
- **HIGH NOISE IMMUNITY**  
 $V_{NIH} = V_{NIL} = 28\% V_{CC} \text{ (MIN)}$
- **OUTPUT DRIVE CAPABILITY**  
 15 LSTTL LOADS
- **SYMMETRICAL OUTPUT IMPEDANCE**  
 $|I_{OH}| = I_{OL} = 6 \text{ mA (MIN)}$ .
- **BALANCED PROPAGATION DELAYS**  
 $t_{PLH} = t_{PHL}$
- **HIGH NOISE IMMUNITY**  
 $V_{NIH} = V_{NIL} = 28\% V_{CC} \text{ (MIN)}$ .
- **WIDE OPERATING VOLTAGE RANGE**  
 $V_{CC} \text{ (OPR)} = 2 \text{ V to } 6 \text{ V}$
- **PIN AND FUNCTION COMPATIBLE**  
 WITH 54/74LS242/243



### DESCRIPTION

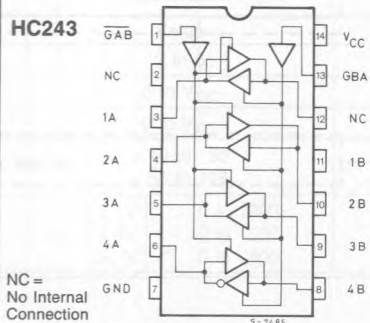
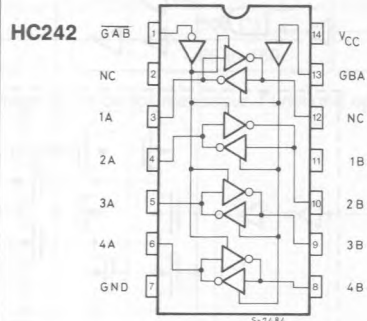
The M54/74HC242 and the M54/74HC243 are high speed CMOS QUAD BUS TRANSCEIVER (3-STATE) fabricated in silicon gate C<sup>2</sup>MOS technology. They have the same high speed performance of LSTTL combined with true CMOS low power consumption.

The M54/74HC242,243 are 3-STATE bi-directional inverting and non-inverting buffers and are intended for two-way asynchronous communication between data buses. They have high drive current outputs which enable high speed operation when driving large bus capacitances.

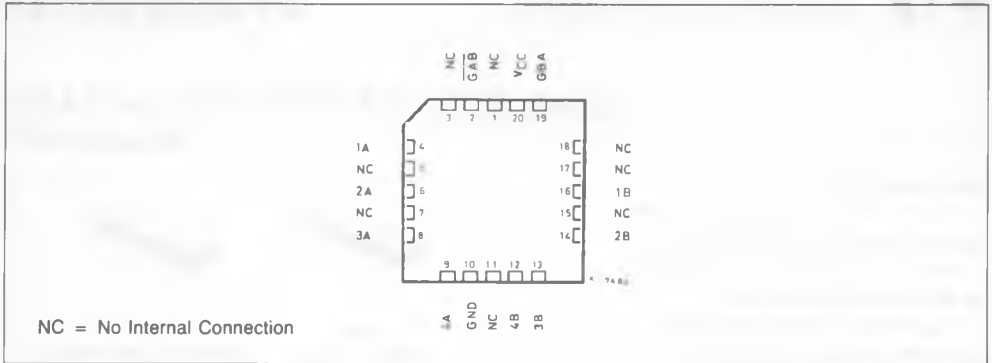
Each device has one active high enable (GBA), and one active low enable (GAB). GBA enables the A outputs and GAB enables the B outputs.

All inputs are equipped with protection circuits against static discharge and transient excess voltage.

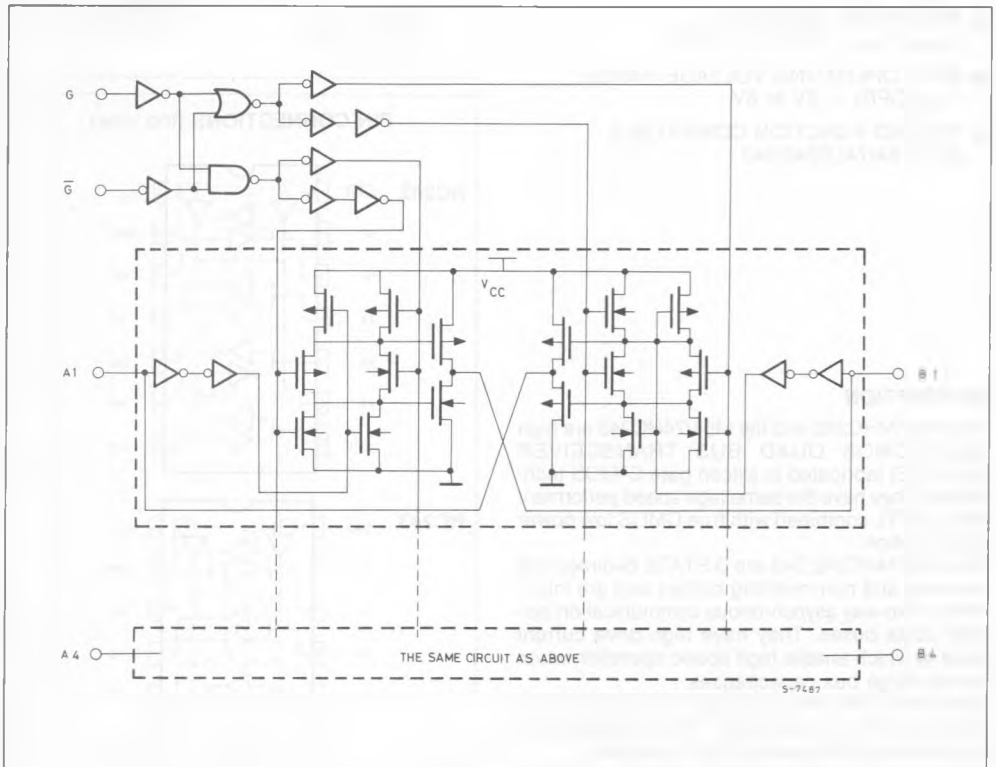
### PIN CONNECTIONS (top view)



CHIP CARRIER



LOGIC DIAGRAM



## TRUTH TABLE

INPUTS		FUNCTION		OUTPUTS	
$\overline{GAB}$	GAB	A BUS	B BUS	HC242	HC243
H	H	OUTPUT	INPUT	$A = \overline{B}$	$A = B$
L	L	INPUT	OUTPUT	$B = \overline{A}$	$B = A$
H	L	HIGH IMPEDANCE		Z	Z
L	H	HIGH IMPEDANCE		Z	Z

Z = HIGH IMPEDANCE

## ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
$V_{CC}$	Supply Voltage	- 0.5 to 7	V
$V_I$	DC Input Voltage	- 0.5 to $V_{CC} + 0.5$	V
$V_O$	DC Output Voltage	- 0.5 to $V_{CC} + 0.5$	V
$I_{IK}$	DC Input Diode Current	$\pm 20$	mA
$I_{OK}$	DC Output Diode Current	$\pm 20$	mA
$I_O$	DC Output Source Sink Current Per Output Pin	$\pm 25$	mA
$I_{CC}$ or $I_{GND}$	DC $V_{CC}$ or Ground Current	$\pm 70$	mA
$P_D$	Power Dissipation	500 (*)	mW
$T_{stg}$	Storage Temperature	- 65 to 150	$^{\circ}C$

Absolute Maximum Ratings are those values beyond which damage to the device may occur. Functional operation under these condition is not implied.

(\*) 500 mW:  $\cong 65^{\circ}C$  derate to 300 mW by 10 mW/ $^{\circ}C$ :  $65^{\circ}C$  to  $85^{\circ}C$ .

## RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter	Value	Unit	
$V_{CC}$	Supply Voltage	2 to 6	V	
$V_I$	Input Voltage	0 to $V_{CC}$	V	
$V_O$	Output Voltage	0 to $V_{CC}$	V	
$T_A$	Operating Temperature	74HC Series 54HC Series	- 40 to 85 - 55 to 125	$^{\circ}C$
$t_r, t_f$	Input Rise and Fall Time	$V_{CC}$ { 2 V 4.5V 6 V	0 to 1000 0 to 500 0 to 400	ns

## DC SPECIFICATIONS

Symbol	Parameter	V <sub>CC</sub>	Test Condition	T <sub>A</sub> = 25°C 54HC and 74HC			- 40 to 85°C 74HC		- 55 to 125°C 54HC		Unit	
				Min.	Typ.	Max.	Min.	Max.	Min.	Max.		
V <sub>IH</sub>	High Level Input Voltage	2.0		1.5	—	—	1.5	—	1.5	—	V	
		4.5		3.15	—	—	3.15	—	3.15	—		
		6.0		4.2	—	—	4.2	—	4.2	—		
V <sub>IL</sub>	Low Level Input Voltage	2.0		—	—	0.5	—	0.5	—	0.5	V	
		4.5		—	—	1.35	—	1.35	—	1.35		
		6.0		—	—	1.8	—	1.8	—	1.8		
V <sub>OH</sub>	High Level Output Voltage	2.0	V <sub>I</sub>	I <sub>O</sub>	1.9	2.0	—	1.9	—	1.9	—	V
		4.5	V <sub>IH</sub> or V <sub>IL</sub>	- 20 μA	4.4	4.5	—	4.4	—	4.4	—	
		6.0			5.9	6.0	—	5.9	—	5.9	—	
		4.5	6.0 mA - 7.8 mA	4.18	4.31	—	4.13	—	4.10	—		
6.0	5.68	5.8		—	5.63	—	5.60	—				
V <sub>OL</sub>	Low Level Output Voltage	2.0	V <sub>IH</sub> or V <sub>IL</sub>	20 μA	—	0.0	0.1	—	0.1	—	0.1	V
		4.5			—	0.0	0.1	—	0.1	—	0.1	
		6.0			—	0.0	0.1	—	0.1	—	0.1	
		4.5			6.0 mA 7.8 mA	—	0.17	0.26	—	0.33	—	
6.0	—	0.18	0.26	—		0.33	—	0.40				
I <sub>I</sub>	Input Leakage Current	6.0	V <sub>I</sub> = V <sub>CC</sub> or GND	—	—	±0.1	—	±1.0	—	±1.0	μA	
I <sub>OZ</sub>	3-State Output Off-State current	6.0	V <sub>I</sub> = V <sub>IH</sub> or V <sub>IL</sub> V <sub>O</sub> = V <sub>CC</sub> or GND	—	—	±0.5	—	±5.0	—	±10	μA	
I <sub>CC</sub>	Quiescent Supply Current	6.0	V <sub>I</sub> = V <sub>CC</sub> or GND	—	—	4	—	40	—	80	μA	

AC ELECTRICAL CHARACTERISTICS (C<sub>L</sub> = 50pF, Input t<sub>r</sub> = t<sub>f</sub> = 6ns)

Symbol	Parameter	V <sub>CC</sub>	Test Condition	T <sub>A</sub> = 25°C 54HC and 74HC			- 40 to 85°C 74HC		- 55 to 125°C 54HC		Unit
				Min.	Typ.	Max.	Min.	Max.	Min.	Max.	
t <sub>TLH</sub> t <sub>THL</sub>	Output Transition Time Output	2.0		—	25	60	—	75	—	90	ns
		4.5		—	7	12	—	15	—	18	
		6.0		—	6	10	—	13	—	15	
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation Delay Time (HC242)	2.0		—	48	100	—	125	—	150	ns
		4.5		—	12	20	—	25	—	30	
		6.0		—	10	17	—	21	—	26	
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation Delay Time (HC243)	2.0		—	44	90	—	115	—	135	ns
		4.5		—	11	18	—	23	—	27	
		6.0		—	9	15	—	20	—	23	
t <sub>PZH</sub> t <sub>PZL</sub>	3-State Output Enable Time	2.0	R <sub>L</sub> = 1kΩ	—	72	145	—	180	—	220	ns
		4.5		—	18	29	—	36	—	44	
		6.0		—	15	25	—	31	—	38	

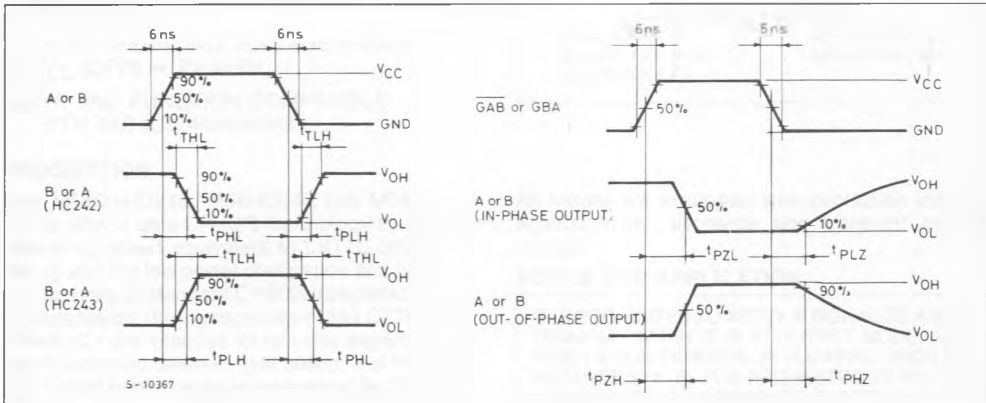
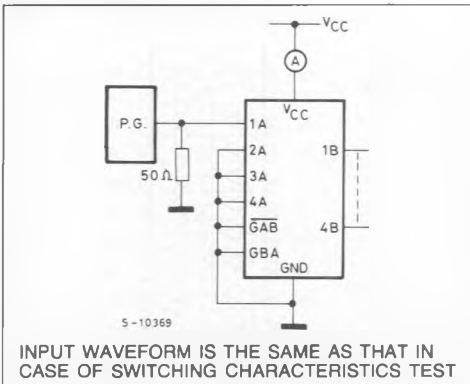
AC ELECTRICAL CHARACTERISTICS ( $C_L = 50\text{pF}$ , Input  $t_r = t_f = 6\text{ns}$ )

Symbol	Parameter	$V_{CC}$	Test Condition	$T_A = 25^\circ\text{C}$ 54HC and 74HC			$-40$ to $85^\circ\text{C}$ 74HC		$-55$ to $125^\circ\text{C}$ 54HC		Unit
				Min.	Typ.	Max.	Min.	Max.	Min.	Max.	
$t_{PHZ}$	3-State Output	2.0	$R_L = 1\text{k}\Omega$	—	84	150	—	190	—	225	ns
$t_{PLZ}$	Disable Time	4.5		—	21	30	—	38	—	45	
		6.0		—	18	26	—	33	—	38	
$C_{IN}$	Input Capacitance		GAB, GBA	—	5	10	—	10	—	10	pF
$C_{I/O}$	Bus Terminal Input Capacitance		An, Bn	—	13	—	—	—	—	—	pF
$C_{PD} (*)$	Power Dissipation		M54/74HC242	—	42	—	—	—	—	—	pF
	Capacitance		M54/74HC243	—	36	—	—	—	—	—	

Note (\*)  $C_{PD}$  is defined as the value of the IC's internal equivalent capacitance which is calculated from the operating current consumption without load. (Refer to Test Circuit)

Average operating current is:  $I_{CC(opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/4$  (per circuit)

## SWITCHING CHARACTERISTICS TEST WAVEFORM

TEST CIRCUIT  $I_{CC}$  (Opr.) $C_{PD}$  CALCULATION

$C_{PD}$  is to be calculated with the following formula by using the measured value of  $I_{CC}$  (Opr.) in the test circuit opposite

$$C_{PD} = \frac{I_{CC} \text{ (Opr.)}}{f_{IN} \cdot V_{CC}}$$

In determining the typical value of  $C_{PD}$ , a relatively high frequency of 1MHz was applied to  $f_{IN}$ , in order to eliminate any error caused by the quiescent supply current